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Sub Code: EEC703

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**B.TECH**  
**(SEM. VII) THEORY EXAMINATION 2017-18**  
**VLSI DESIGN**

*Time: 3 Hours**Total Marks: 100*

- Note:** 1. Attempt all Sections.  
 2. Assume any missing data.

**SECTION A**

- 1. Attempt all questions in brief. 2 x10 = 20**
- a. Why we need a low power VLSI circuits in today's scenario?
  - b. Write short notes on controllability and observability.
  - c. How the latch up problem can be overcome?
  - d. Define Interconnect scaling.
  - e. Define the terms Defects, Errors and Faults.
  - f. Why we prefer CMOS transmission gates over other gates?
  - g. Define logical effort with example.
  - h. What are the various ways to reduce the delay time of a CMOS inverter?
  - i. What is meant by Stuck-at-1 (s-a-1) fault and stuck-at-0 (s-a-0) fault?
  - j. Draw the stick diagram of EXOR gate.

**SECTION B**

- 2. Attempt any three of the following: 10 x 3 = 30**
- a. Draw the Y-Chart and explain the VLSI design process.
  - b. Enlist the layout design process and design rules of CMOS circuit. Draw a stick diagram of CMOS NOR gate.
  - c. Explain two input XOR gate using CMOS logic circuits, TG gate and Pass Transistor logic.
  - d. Consider a CMOS inverter circuit with the following parameters:  $V_{DD} = 5V, V_{TO,n} = 0.8V, V_{TO,p} = -0.1V, \mu_n C_{ox} = 50\mu A/v^2, \mu_p C_{ox} = 20\mu A/v^2, \lambda=0$ . Both transistor have a channel length of  $L_n = L_p = 1\mu m$ , the total output load capacitance of this circuit is  $C_{out} = 2pF$ , which is independent of transistor dimensions.
    - i) Determine the channel width of the nMOS and pMOS transistors such that the switching threshold voltage is equal to 2.2V and the output rise time is  $\tau_{rise} = 5ns$ .
    - ii) Calculate the average propagation delay time  $\tau_p$
  - e. Discuss the operation of CMOS SRAM cell circuit. Also describe in brief Adiabatic CMOS logic. Design an adiabatic 2 input AND/NAND.

**SECTION C**

- 3. Attempt any one parts of the following: 10 x 1 = 10**
- a. Enlist the classification of CMOS digital logic families. Why CMOS VLSI design is better techniques than its counter parts?
  - b. What are the various processes of CMOS fabrication? Illustrate the main steps in a typical n-well process.

**4. Attempt any one parts of the following: 10 x 1 = 10**

- a) Prove that pull-up to pull-down ratio for an NMOS inverter driven by another NMOS inverter is 4/1. Implement the Boolean function  $f(A,B,C)=\overline{A}BC+\overline{A}\overline{B}C+A\overline{B}\overline{C}$  using CMOS logic.
- b) Explain the concept of MOSFET as switches with the help of diagram. Calculate the delay involved in cascaded pass transistors.

**5. Attempt any one parts of the following: 10 x 1 = 10**

- a) Derive and explain the working of CMOS inverter with its VTC characteristics. Also calculate the  $V_{OL}$ ,  $V_{OH}$ ,  $V_{IL}$ ,  $V_{IH}$  and  $V_{TH}$  for the CMOS inverter.
- b) Explain CMOS edge triggered flip flop with the help of input and output waveforms.

**6. Attempt any one parts of the following: 10 x 1 = 10**

- a) Discuss the operation of single stage shift register circuits Design a SR flip-flop using CMOS circuits.
- b) What are the various sources of power dissipation in CMOS circuits? Discuss in detail the variable threshold CMOS circuits.

**7. Attempt any one parts of the following: 10 x 1 = 10**

- a) Design the circuit describe by Boolean function  $Y = A.(B+C)(D+E)$  using CMOS logic .calculate the equivalent CMOS inverter circuit for simultaneous switching of all inputs assuming that  $[W/L]=5$  for pMOS transistor and  $[W/L]=2$  for nMOS transistors.
- b) Explain the following:
  - i) Ad-Hoc testable design techniques
  - ii) Built- in self test (BIST) techniques